Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/534,494	LEWIN ET AL.	
Examiner	Art Unit	-
Patrick I Lee	2878	

	SEAR	CHED	
Class	Subclass	Date	Examiner
250	221, 222.1	9(14)06 9/26/06	PL
356	4.01-4.09		PL
Updated	search	1/19/2007	PL
Updated	search	1/24/2007	PL
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		<u></u>	
			<u></u>

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	9/14/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	9/25/2006	PL _.
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	1/19/2007	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	1/24/2007	PL